Test Org.*	Device	Function	Technology	Mfr.	Proton Energy (MeV)	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LU_{th} (MeV)	LU Xsection (cm^2/bit)	Fac.	Remarks 30-Aug-99
		Other Linears											
	Note: Entries in **RED** indicate data added since the 1997 Compendium.												
GSFC	**PFORX12**	**Data Transmission Receiver**		**ONI**	**62.5**				**1997**			**UCD**	**O'Bryan, et al, 98IEEE Wrkshp Rec., pg 39. No bit errors up 30 krads. Error bursts at 85 krads.**
GSFC	**PFOTX12**	**Data Transmission Xmtr**		**ONI**	**62.5**				**1997**			**UCD**	**O'Bryan, et al, 98IEEE Wrkshp Rec., pg 39. No bit errors up 30 krads. Error bursts at 85 krads.**
Legend													
	Manufacturers: ADI - Analog Devices, Inc; BAL - Ball Efatrom; CCT - C-Cam Technology; DDC - Data Devices Corp; HAR - Harris Corp; LTN Linear Technology; MOT - Motorola Semiconductor; NSC - National Semiconductor;												
	OBT - Orbit Semiconductors; ONI - Optical Networks, Inc; PLS - GEC-Plessey Semiconductors; QSI - Quality Semi Inc; SGN - Signetics; SLG - Silicon General Corp; UTR - United Technologies Microelectronic Center												
	Test Organizations			**Radiation Test Facilities**									
	GSFC - Goddard Space Flight Center, Greenbelt, MD			UCD - University of California at Davis, Crocker Nuclear Laboratory, Davis, CA									